D²PAK (TO-263)



6R199P-VB TO263 Datasheet

N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY					
V _{DS} (V) at T _J max.	650				
R _{DS(on)} (Ω) at 25 °C	$V_{GS} = 10 V$	0.19			
Q _g max. (nC)	106				
Q _{gs} (nC)	14				
Q _{gd} (nC)	33				
Configuration	Single				

FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qq
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
 - Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Consumer and computing
- ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

ABSOLUTE MAXIMUM RATINGS ($T_c = 25 \degree C$, unless otherwise noted)								
PARAMETER			SYMBOL	LIMIT	UNIT			
Drain-Source Voltage			V _{DS}	650	V			
Gate-Source Voltage			V _{GS}	± 30	v			
Continuous Drain Current (T ₁ = 150 °C)	V _{GS} at 10 V	T _C = 25 °C T _C = 100 °C	I	20				
Continuous Drain Current (1j = 150°C)	VGS AL TO V	T _C = 100 °C	Ι _D	13	А			
Pulsed Drain Current ^a			I _{DM}	60				
Linear Derating Factor				1.7	W/°C			
Single Pulse Avalanche Energy ^b			E _{AS}	367	mJ			
Maximum Power Dissipation			PD	208	W			
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +150	°C				
Drain-Source Voltage Slope	T _J = 125 °C		dV/dt	37	V/ns			
Reverse Diode dV/dt ^d		uv/di	31	v/ns				
Soldering Recommendations (Peak Temperature) ^c	for 10 s			300	°C			

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

S N-Channel MOSFET

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.





Maximum Junction-to-Ambient R _{thuk} - 62 °C/W Maximum Junction-to-Case (Drain) R _{thuc} - 0.5 °C/W SPECIFICATIONS (T _J = 25 °C, unless otherwise noted) Test conditions Min. TYP. MAX. UN Static Drain-Source Breakdown Voltage V _{DS} V _{DS} = 0 V, I _D = 250 µA 650 - - V/V Organ-Source Breakdown Voltage V _{DS} V _{DS} = 0 V, I _D = 250 µA 650 - - V/V Organ-Source Deficient ΔV _{DS} T Reference to 25 °C, I _D = 1 mA - 0.67 - V/V Gate-Source Leakage I _{DSS} V _{DS} = 250 µA 2 - 4 V Gate-Source Leakage I _{DSS} V _{DS} = 520 V, V _{DS} = 0 V - - 1 µ/V Zero Gate Voltage Drain Current I _{DSS} V _{DS} = 520 V, V _{DS} = 0 V - - 1 µ/V Ipul Capacitance G _{Oss} V _{DS} = 10 V, I _D = 11 A - 7.0 - S Output Capacitance, Energy	THERMAL RESISTANCE RAT	INGS							
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	PARAMETER	SYMBOL	TYP.				UNIT		
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Ambient	R _{thJA}	-						
$\begin{array}{ c c c c c c } \hline PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UN Static $$$ The state of $	Maximum Junction-to-Case (Drain)		-	- 0.5			- °C/W		
$\begin{array}{ c c c c c c } \hline PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UN Static $$$ The state of $									
$\begin{array}{ c c c c c c } \hline PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UN Static $$$ The state of $	SPECIFICATIONS (T,I = 25 °C,	unless otherw	ise noted)						
$\begin{array}{ c c c c c c } \hline \mbox{Drain-Source Breakdown Voltage} & V_{DS} & V_{DS} & V_{DS} & 25 \ C, \ I_D & = 1 \ A & - & 0.67 & - & V \\ V_{OS} & Temperature Coefficient & \Delta V_{OS} T_J & Reference to 25 \ C, \ I_D & = 1 \ A & - & 0.67 & - & V \\ \hline \mbox{Gate-Source Threshold Voltage (N)} & V_{GS(m)} & V_{OS} & V_{GS, \ D} & 250 \ \mu & 2 & - & 4 & V \\ \hline \mbox{Gate-Source Intreshold Voltage (N)} & V_{GS(m)} & V_{OS} & V_{GS, \ D} & 20 \ V & - & - & \pm 1 \ \mu & V \\ \hline \mbox{Gate-Source Co-State Resistance} & R_{DS(m)} & V_{OS} & = 520 \ V, \ V_{OS} & = 0 \ V & - & - & 1 \ \mu & V \\ \hline \mbox{Drain-Source On-State Resistance} & R_{DS(m)} & V_{OS} & = 10 \ V \ V_{DS} & = 30 \ V, \ V_{DS} & = 0 \ V & - & - & 500 \ \mu & V \\ \hline \mbox{Drain-Source On-State Resistance} & R_{DS(m)} & V_{OS} & = 10 \ V \ V_{DS} & = 30 \ V, \ I_D & = 11 \ A & - & 7.0 & - & S \\ \hline \mbox{Drain-Source On-State Resistance} & R_{DS(m)} & V_{OS} & = 0 \ V \ V_{DS} & = 30 \ V, \ I_D & = 11 \ A & - & 7.0 & - & S \\ \hline \mbox{Drain-Source On-State Resistance} & R_{DS(m)} & V_{OS} & = 0 \ V \ V_{DS} & = 0 \ V, \ V_{DS} & = 10 \ V, \ V_{DS} & = 0 \ V, \ V_{DS} & = 0 \ V \ V_{DS} & = 10 \ V, \ V_{DS} & = 0 \ V \ S \ S & = 0 \ V \ S \ S & = 0 \ V \ S \ S & = 0 \ V \ S \ S & = 0 \ V \ S \ S & = 0 \ V \ S \ S & = 0 \ V \ S \ S \ S \ S \ S \ S \ S \ S \ S$	PARAMETER	1	1		ONS	MIN.	TYP.	MAX.	UNI
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Static					1			I
	Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D = 2	50 µA	650	-	-	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	V _{DS} Temperature Coefficient		Referenc	e to 25 °C, I	_D = 1 mA	-	0.67	-	V/°C
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Threshold Voltage (N)					2	-	4	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $						-	-	± 100	nA
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Gate-Source Leakage	IGSS		$V_{GS} = \pm 30$ V	V	-	-	± 1	μA
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$						-	-	1	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate Voltage Drain Current	IDSS				-	-	500	μA
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	I _D	= 11 A	-	0.19	-	Ω
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Forward Transconductance				-	7.0	-	S	
Output Capacitance C_{oss} $V_{DS} = 100 \text{ V},$ f = 1 MHz-105-Reverse Transfer Capacitance C_{rss} Γ_{rss} Γ_{rss} -105-Effective Output Capacitance, Energy Related a $C_{o(er)}$ $V_{DS} = 0 \text{ V}$ to 520 V, $V_{GS} = 0 \text{ V}$ -84-Effective Output Capacitance, Time Related b $C_{o(tr)}$ $V_{DS} = 0 \text{ V}$ to 520 V, $V_{GS} = 0 \text{ V}$ -84-Total Gate Charge Q_g $V_{GS} = 10 \text{ V}$ $I_D = 11 \text{ A}, V_{DS} = 520 \text{ V}$ -71106Gate-Drain Charge Q_{gd} $V_{GS} = 10 \text{ V}$ $I_D = 11 \text{ A}, V_{DS} = 520 \text{ V}$ -14-Turn-On Delay Time $t_{d(on)}$ $V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$ -68102Fall Time t_r $V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$ -68102Fall Time t_r r_r -4284Gate Input Resistance R_g f = 1 MHz, open drain-0.78-Drain-Source Body Diode Characteristics r_r r_r r_r r_r r_r Pulsed Diode Forward Current I_S MOSFET symbol showing the integral reverse $p - n$ junction diode- 0.9 1.2 V Diode Forward Voltage V_{SD} $T_J = 25 \text{ °C}, I_S = 11 \text{ A}, V_{GS} = 0 \text{ V}$ - 0.9 1.2 V Reverse Recovery Time t_{rr} $T_J = 25 \text{ °C}, I_S = 25 \text{ V}$ - 1.2 $ 1.2$ $-$	Dynamic	•	-			•	•	•	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Input Capacitance	C _{iss}		$V_{cc} = 0 V$		-	2322	-	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Output Capacitance	C _{oss}		V _{DS} = 100 V,		-	105	-	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance	C _{rss}				-	4	-	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V_{DS} = 0 V to 520 V, V_{GS} = 0 V		-	84	-	pF	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	293	-		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Total Gate Charge	Qg		V _{GS} = 10 V I _D = 11 A, V _{DS} = 520 V		-	71	106	nC
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Charge	Q _{gs}	$V_{GS} = 10 V$			-	14	-	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Drain Charge					-	33	-	
Turn-Off Delay Time $t_{d(off)}$ $V_{GS} = 10 \text{ V}, \text{ H}_{g} = 9.1 \Omega$ $ 68$ 102 Fall Time t_{f} $ 42$ 84 Gate Input Resistance R_{g} $f = 1 \text{ MHz}$, open drain $ 0.78$ $ \Omega$ Drain-Source Body Diode CharacteristicsMOSFET symbol showing the integral reverse $ 21$ A Pulsed Diode Forward Current I_{SM} MOSFET symbol showing the integral reverse $ 21$ A Diode Forward Voltage V_{SD} $T_{J} = 25 ^{\circ}C, I_{S} = 11 A, V_{GS} = 0 V$ $ 0.9$ 1.2 V Reverse Recovery Time t_{rr} $T_{J} = 25 ^{\circ}C, I_{F} = I_{S} = 11 A,$ dl/dt = $100 \text{ A/µs}, V_{R} = 25 V$ $ 1.2$ $ \mu$	Turn-On Delay Time					-	22	44	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Rise Time	t _r	V _{DD} =	V _{DD} = 520 V, I _D = 11 A,		-	34	68	1
Fall Time t_f -4284Gate Input Resistance R_g $f = 1 \text{ MHz}$, open drain-0.78- Ω Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode Current I_S MOSFET symbol showing the integral reverse21APulsed Diode Forward Current I_{SM} P_r n junction diode53ADiode Forward Voltage V_{SD} $T_J = 25 \ ^\circ C$, $I_F = I_S = 11 \ A$, dl/dt = 100 A/µs, $V_B = 25 \ V$ -0.91.2V	Turn-Off Delay Time	t _{d(off)}	$V_{GS} = 10 \text{ V}, \text{ R}_{g} = 9.1 \Omega$		-	68	102	ns	
Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentIsMIsMTJ = 25 °C, Is = 11 A, VGS = 0 V-0.91.2VDiode Forward VoltageVSDTJ = 25 °C, Is = 11 A, VGS = 0 V-0.91.2VReverse Recovery TimetrrTJ = 25 °C, Is = 11 A, dI/dt = 100 A/µs, Vg = 25 V-1.60-ns	Fall Time				-	42	84		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω	
Continuous source-brain bloce outrentIsshowing the integral reverse $p - n$ junction diodeIIIIAPulsed Diode Forward CurrentIsIs $p - n$ junction diodeIsIsIsADiode Forward VoltageV_{SDT_J = 25 °C, I_S = 11 A, V_{GS} = 0 V-0.91.2VReverse Recovery Time t_{rr} $T_J = 25 °C, I_F = I_S = 11 A, dI/dt = 100 A/\mus, V_B = 25 V-160-ns$	Drain-Source Body Diode Characterist	ics							
Pulsed Diode Forward CurrentIsmIntegral reverse p - n junction diode53Diode Forward Voltage V_{SD} $T_J = 25 ^{\circ}C$, $I_S = 11 A$, $V_{GS} = 0 V$ -0.91.2VReverse Recovery Time t_{rr} $T_J = 25 ^{\circ}C$, $I_F = I_S = 11 A$, dl/dt = 100 A/µs, $V_B = 25 V$ -160-ns	Continuous Source-Drain Diode Current	I _S				-	-	21	
Reverse Recovery Time t_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = I_S = 11 \ A$, $dI/dt = 100 \ A/\mu$ s, $V_B = 25 \ V$ -160-ns	Pulsed Diode Forward Current	I _{SM}			-	-	53	А	
Reverse Recovery Time t_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = I_S = 11 \ A$, $dI/dt = 100 \ A/\mu$ s, $V_B = 25 \ V$ -160-ns	Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V		-	0.9	1.2	V	
Reverse Recovery Charge Q_{rr} $T_J = 25 \ ^{\circ}C$, $I_F = I_S = 11 \ A$, $dI/dt = 100 \ A/\mu s$, $V_B = 25 \ V$ -1.2- μC	Reverse Recovery Time		T _J = 25 °C, I _F = I _S = 11 A,		-	160	- 1	ns	
Δl/dt = 100 A/μs, v _R = 25 V					-		- 1	μC	
	Reverse Recovery Current	I _{RRM}	ai/dt =	dl/dt = 100 A/µs, V _R = 25 V		-	14	-	A

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

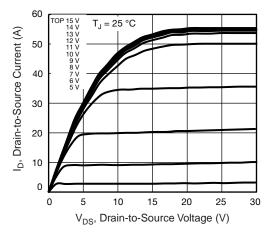


Fig. 1 - Typical Output Characteristics



Fig. 2 - Typical Output Characteristics

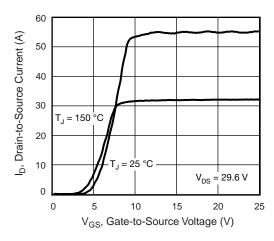


Fig. 3 - Typical Transfer Characteristics

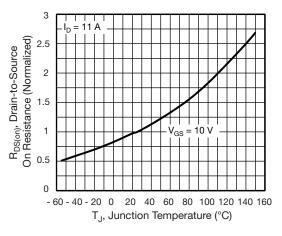


Fig. 4 - Normalized On-Resistance vs. Temperature

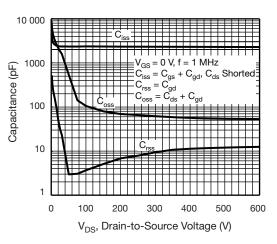


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}

6R199P-VB TO263



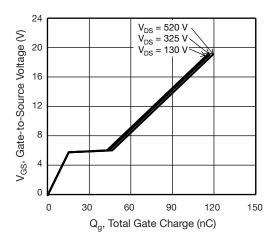


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

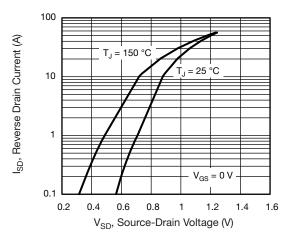


Fig. 8 - Typical Source-Drain Diode Forward Voltage

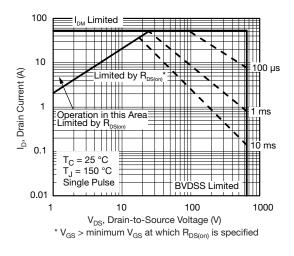


Fig. 9 - Maximum Safe Operating Area

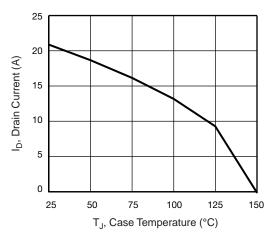


Fig. 10 - Maximum Drain Current vs. Case Temperature



Fig. 11 - Temperature vs. Drain-to-Source Voltage



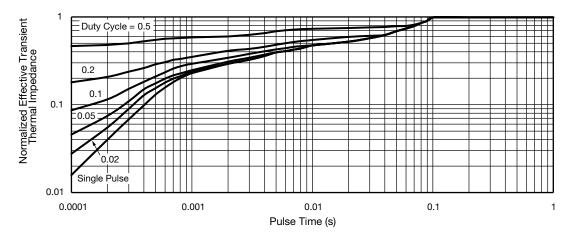


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case



Fig. 13 - Switching Time Test Circuit



Fig. 14 - Switching Time Waveforms

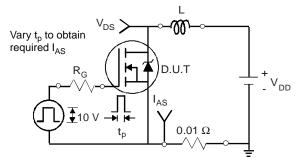


Fig. 15 - Unclamped Inductive Test Circuit

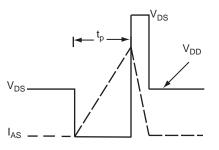


Fig. 16 - Unclamped Inductive Waveforms

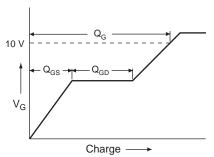
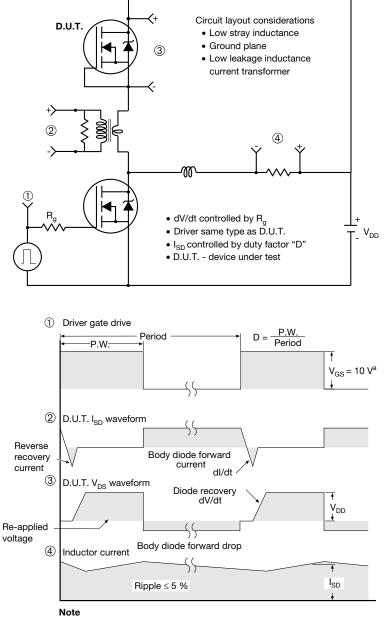


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit

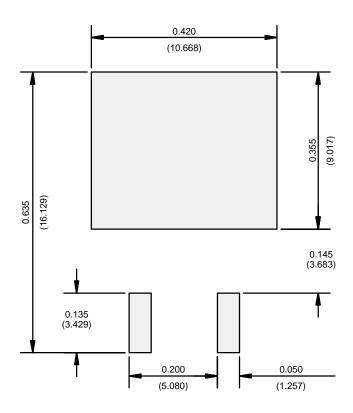


a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel



RECOMMENDED MINIMUM PADS FOR D²PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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